


<b>Search Notes</b>  	<b>Application/Control No.</b>  10758863	<b>Applicant(s)/Patent Under Reexamination</b>  STASZEWSKI ET AL.
	<b>Examiner</b>  Flores, Leon	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	224, 226, 375, 376	3/22/2007	LF
327	141, 147, 156	3/22/2007	LF
455	423, 425	3/12/2008	LF

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE Chieh Fan in regards to the patentability of claim 1 & 32	3/22/2007	LF
Consulted with SPE David Payne in regards to the patentability of the claims.	3/26/2007	LF
Checked for double patenting.	3/22/2007	LF
Consulted with SPE David Payne in regards to the amendments.	9/10/2007	LF
Consulted with SPE David Payne in regards to the AF.	11/28/2007	LF
Consulted with SPE David Payne in regards to the references used to reject the claims.	3/19/2008	LF
Consulted with SPE David Payne in regards to the arguments.	12/19/2008	LF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/L. F./ Examiner: Art Unit 2611	
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